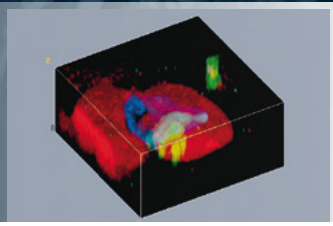
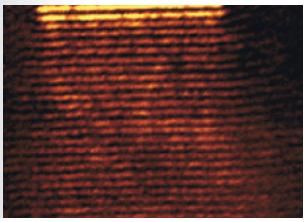
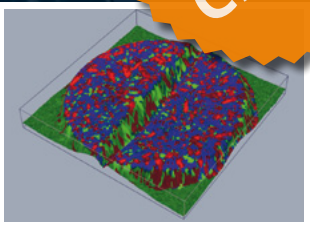
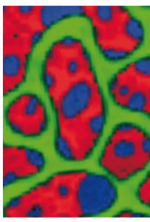
WITec
focus innovations

Santiago de Compostela
17. April 2018

FREE OF CHARGE



3D Raman Imaging Meets AFM and SEM

Chemical and Structural Material Characterization from the Nano- to the Millimeter Range

It´s our pleasure to invite you to our workshop in Spain to learn more about high-resolution chemical and structural imaging on the nano- to the mm-scale. Talk with our experts about all our solutions for Raman imaging, Atomic Force Microscopy, Scanning Near-field Optical Microscopy or Profilometry. See a live demo of our microscope system and its capabilities in combining the various techniques. Participation is free of charge but requires registration as the number of participants is limited.

For any further information or questions please contact:
elena.bailo@witec.de

USC
UNIVERSIDADE DE SANTIAGO DE COMPOSTELA

Program

17.04. 2018

Workshop venue

Aula Seminario
Edificio CACTUS-Campus Sur
Universidad de Santiago de Compostela
15706 Santiago de Compostela (Spain)
http://www.usc.es/es/info_xeral/localizacion/santiago.html

Universidad de Santiago de Compostela

09:30 - 09:45	Prof. Dr. Isabel Rodriguez-Moldes Rey Welcome WITec & USC
09:45 - 10:30	Dr. Elena Bailo Combining High Resolution Confocal Raman Imaging, Scanning Probe Microscopy and SEM
10:30 - 11:15	Prof. Dr. Massimo Lazzari SERS-active substrates for the detection of art materials and oligomeric degradation products
11:15 - 11:45	Coffee Break
11:45 - 13:00	Equipment Demonstration & Discussion

People

Prof. Dr. Isabel Rodriguez-Moldes Rey
Vicer-rector of Research and Innovation at the University of Santiago de Compostela

Prof. Dr. Massimo Lazzari
Associate Professor at the University of Santiago de Compostela

Dr. Elena Bailo
Application Scientist and Area Manager Spain & Portugal at WITec GmbH

3D Raman Imaging Meets AFM and Profilometry

Deadline for Registration: 6th of April 2018

For registration please visit following website:
https://www.witec.de/resources-and-education/workshops/workshop-santiago-de-compostela/